



Ohmic Contact for SiC CMOS Devices

Microelectronics-Photonic
Materials & Devices

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Energy Materials & Devices

Background/Relevance

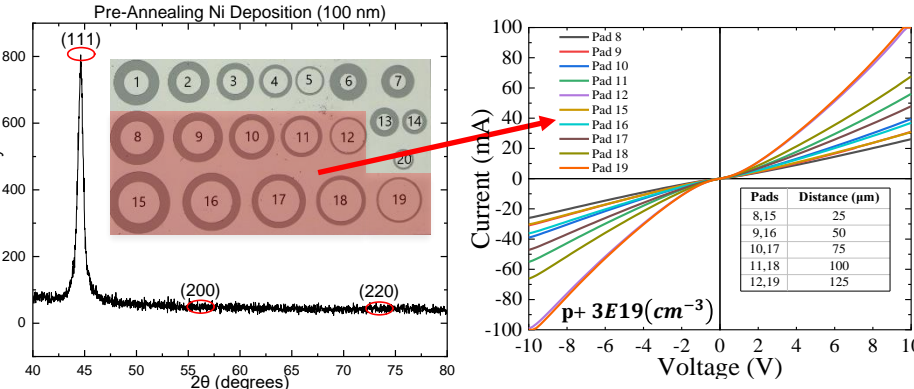
- High demand for high temperature and high performance integrated circuits (ICs) which can replace traditional Si ICs and pack more processing power.
- SiC has a great outlook for automobile integration, power grid infrastructure, and other applications in harsh environments.
- CMOS devices will prove more useful with robust ICs that can maintain integrity in extreme conditions for lengthy durations.

Innovation

- Utilizing multiple materials, an ohmic contact can be formed for both n- and p-type semiconductor materials, which means better switching speeds and higher efficiency processes.

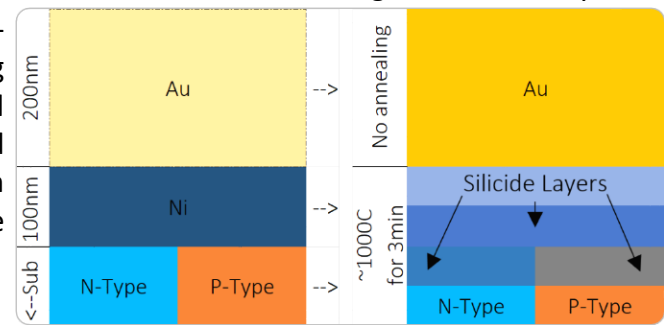
Key Results

- Using a Circular Transfer Line Measurement (CTLM) device, the IV characteristics show linear behavior for P+ devices with a specific contact resistivity of $1.9E - 3(\Omega \cdot cm^2)$.



Approach

- Multilayered Silicide allows for high-quality diffusion of material between SiC-metal interface.
- RTA must be between 900-1100°C with inert gases for bulk layers.
- Short, high-temp annealing allows for small steps in band energy between the substrate and contact.



Conclusions

- A compromise will have to be made between the doping concentration for both types of materials and the quality of the contact which will affect the specific contact resistivity.
- The ohmic behavior of the p+ sample indicates less of a barrier between the substrate and the metal-contact interface.
- Without annealing the contact after deposition, no silicide was able to form, leading to a higher resistance.
- N-type samples will require higher doping concentrations for simultaneous ohmic contacts with this approach.